

2M x 32 DRAM Module

Features

- 72-Pin JEDEC Standard Single-In-Line Memory Module
- Performance:

		-60	-70
t_{RAC}	RAS Access Time	60ns	70ns
t_{CAC}	CAS Access Time	15ns	20ns
t_{AA}	Access Time From Address	30ns	35ns
t_{RC}	Cycle Time	110ns	130ns
t_{PC}	Fast Page Mode Cycle Time	40ns	45ns

- High Performance CMOS process
- Single 5V, $\pm 0.5V$ Power Supply

- All inputs & outputs are fully TTL & CMOS compatible
- Fast Page Mode access cycle
- Refresh Modes: RAS-Only and CBR
- 1024 refresh cycles distributed across 16ms
- 10/10 Addressing (Row/Column)
- Optimized for use in byte-write non-parity applications.
- Au and Sn/Pb versions available

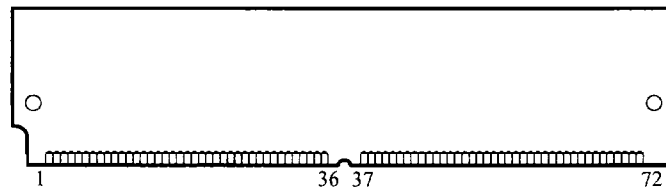
Description

The IBM11D2320BC is an 8MB industry standard 72-pin 4-byte single in-line memory module (SIMM). The module is organized as a 2Mx32 high speed memory array, and is configured as 2 1Mx32 banks - each independently selectable via unique RAS inputs. The assembly is intended for use in 16, 32 and 64 bit applications. It is manufactured with 16 1Mx4 devices, each in either a 350mil or 300mil package, and is compatible with the JEDEC 72-Pin

SIMM standard.

The IBM 72-Pin SIMMs provide a high performance, flexible 4-byte interface in a 4.25" long footprint. Related products include the 2Mx36 parity SIMM, IBM11D2360B, as well as other density offerings and ECC-optimized SIMMs.

Card Outline





Pin Description

$\overline{\text{RAS0}} - \overline{\text{RAS3}}$	Row Address Strobe
$\overline{\text{CAS0}} - \overline{\text{CAS3}}$	Column Address Strobe
$\overline{\text{WE}}$	Read/write input
A0 - A9	Address Inputs
DQ0-7, 9-16, 18-25, 27-34	Data Input/output
V _{CC}	Power (+5V)
V _{SS}	Ground
NC	No Connect
PD1 - PD4	Presence Detects

Pinout

Pin #	Name	Pin #	Name	Pin #	Name	Pin #	Name	Pin #	Name	Pin #	Name
1	V _{SS}	13	A1	25	DQ24	37	NC	49	DQ9	61	DQ14
2	DQ0	14	A2	26	DQ7	38	NC	50	DQ27	62	DQ33
3	DQ18	15	A3	27	DQ25	39	V _{SS}	51	DQ10	63	DQ15
4	DQ1	16	A4	28	A7	40	$\overline{\text{CAS0}}$	52	DQ28	64	DQ34
5	DQ19	17	A5	29	NC	41	$\overline{\text{CAS2}}$	53	DQ11	65	DQ16
6	DQ2	18	A6	30	V _{CC}	42	$\overline{\text{CAS3}}$	54	DQ29	66	NC
7	DQ20	19	NC	31	A8	43	$\overline{\text{CAS1}}$	55	DQ12	67	PD1
8	DQ3	20	DQ4	32	A9	44	$\overline{\text{RAS0}}$	56	DQ30	68	PD2
9	DQ21	21	DQ22	33	$\overline{\text{RAS3}}$	45	$\overline{\text{RAS1}}$	57	DQ13	69	PD3
10	V _{CC}	22	DQ5	34	$\overline{\text{RAS2}}$	46	NC	58	DQ31	70	PD4
11	NC	23	DQ23	35	NC	47	$\overline{\text{WE}}$	59	V _{CC}	71	NC
12	A0	24	DQ6	36	NC	48	NC	60	DQ32	72	V _{SS}

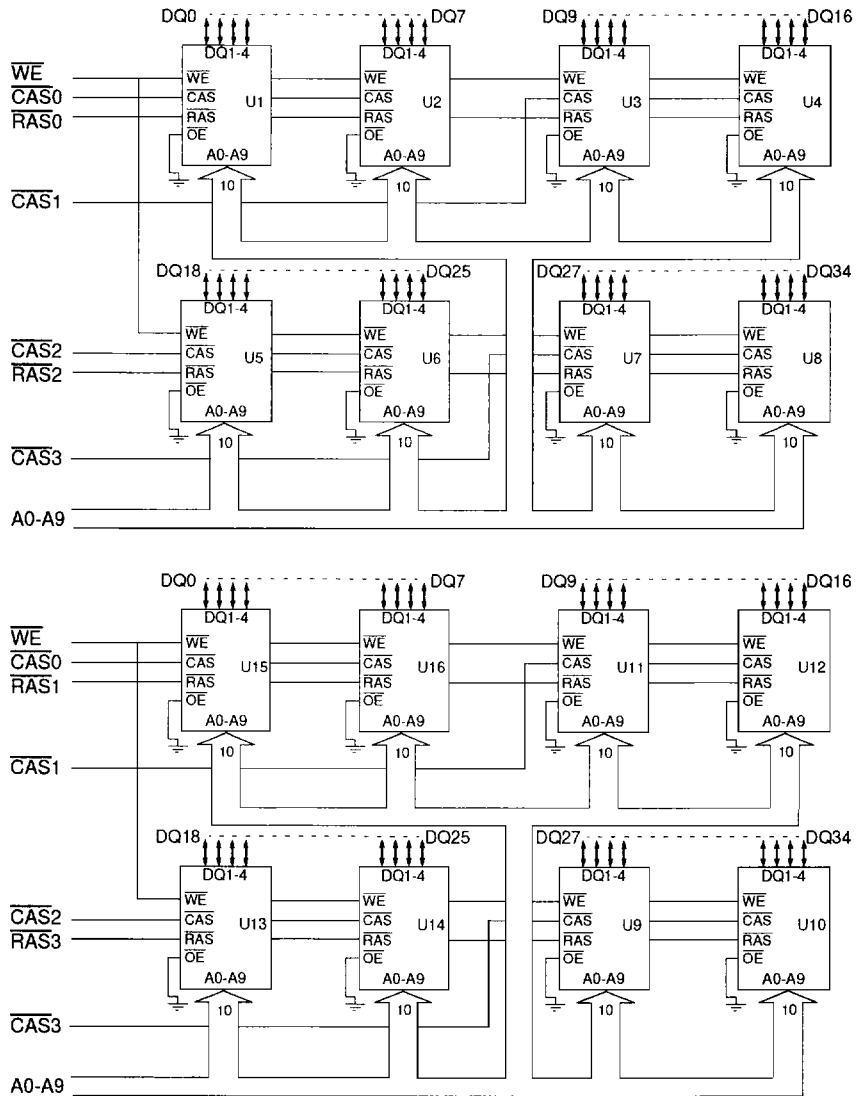
1. DQ numbering is compatible with parity (x36) version.

Ordering Information

Part Number	Organization	Speed	Leads	Dimensions	Notes
IBM11D2320BA-60	2M x 32	60ns	Sn/Pb	4.25" x 1" x .360"	
IBM11D2320BA-70	2M x 32	70ns	Sn/Pb	4.25" x 1" x .360"	
IBM11E2320BA-60	2M x 32	60ns	Au	4.25" x 1" x .360"	
IBM11E2320BA-70	2M x 32	70ns	Au	4.25" x 1" x .360"	
IBM11D2320BC-60	2M x 32	60ns	Sn/Pb	4.25" x 1" x .360"	1
IBM11D2320BC-70	2M x 32	70ns	Sn/Pb	4.25" x 1" x .360"	1
IBM11E2320BC-60	2M x 32	60ns	Au	4.25" x 1" x .360"	1
IBM11E2320BC-70	2M x 32	70ns	Au	4.25" x 1" x .360"	1

1. 'C' revision replaces 'A' revision, all specifications are identical or improved. 'C' revision uses new raw card which is common with IBM11D2360E.

Block Diagram



Truth Table

Function	$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	$\overline{\text{WE}}$	Row Address	Column Address	All DQ bits
Standby	H	X	X	X	X	High Impedance
Read	L	L	H	Row	Col	Valid Data Out
Early-Write	L	L	L	Row	Col	Valid Data In
Fast Page Mode - Read: 1st Cycle	L	H→L	H	Row	Col	Valid Data Out
Subsequent Cycles	L	H→L	H	N/A	Col	Valid Data Out
Fast Page Mode - Write: 1st Cycle	L	H→L	L	Row	Col	Valid Data In
Subsequent Cycles	L	H→L	L	N/A	Col	Valid Data In
$\overline{\text{RAS}}$ -Only Refresh	L	H	X	Row	N/A	High Impedance
$\overline{\text{CAS}}$ -Before- $\overline{\text{RAS}}$ Refresh	H→L	L	H	X	X	High Impedance

Presence Detect

Pin	-60	-70
PD1	NC	NC
PD2	NC	NC
PD3	NC	V _{SS}
PD4	NC	NC

1. NC= OPEN, V_{SS} = GND

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units	Notes
V _{CC}	Power Supply Voltage	-0.5 to 6.5	V	1
V _{IN}	Input Voltage	-0.7 to V _{CC} + 0.7	V	1
V _{OUT}	Output Voltage	-0.7 to V _{CC} + 0.7	V	1
T _{OPR}	Operating Temperature	0 to +70	°C	1
T _{STG}	Storage Temperature	-55 to +125	°C	1
P _D	Power Dissipation	10.6	W	1, 2
I _{OUT}	Short Circuit Output Current	50	mA	1

- Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only, and device functional operation at or above the conditions indicated is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- Maximum power occurs when all banks are active.

Recommended DC Operating Conditions ($T_A = 0$ to 70°C)

Symbol	Parameter	Min	Typ	Max	Units	Notes
V_{CC}	Supply Voltage	4.5	5.0	5.5	V	1
V_{IH}	Input High Voltage	2.4	—	V_{CC}	V	1
V_{IL}	Input Low Voltage	0.0	—	0.8	V	1
1. All voltages referenced to V_{SS} .						

Capacitance ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5.0 \pm 0.5\text{V}$)

Symbol	Parameter	Max	Units	Notes
C_{I1}	Input Capacitance (A0-A9)	90	pF	
C_{I2}	Input Capacitance ($\overline{\text{RAS}}$)	37	pF	
C_{I3}	Input Capacitance ($\overline{\text{CAS}}$)	37	pF	
C_{I4}	Input Capacitance ($\overline{\text{WE}}$)	75	pF	
$C_{I/O}$	Output Capacitance (DQ0-DQ34)	25	pF	

DC Electrical Characteristics ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5 \pm 0.5\text{V}$)

Symbol	Parameter	Min	Max	Units	Notes
I_{CC1}	Operating Current Average Power Supply Operating Current ($\overline{\text{RAS}}$, $\overline{\text{CAS}}$, Address Cycling: $t_{RC} = t_{RC \text{ min}}$)	-60	—	mA	1, 2, 3
		-70	—		
I_{CC2}	Standby Current (TTL) Power Supply Standby Current ($\overline{\text{RAS}} = \overline{\text{CAS}} \geq V_{IH}$)	—	32	mA	
I_{CC3}	$\overline{\text{RAS}}$ Only Refresh Current Average Power Supply Current, $\overline{\text{RAS}}$ Only Mode ($\overline{\text{RAS}}$ Cycling, $\overline{\text{CAS}} \geq V_{IH}$; $t_{RC} = t_{RC \text{ min}}$)	-60	—	mA	1, 3, 4
		-70	—		
I_{CC4}	Fast Page Mode Current Average Power Supply Current, Fast Page Mode ($\overline{\text{RAS}} = V_{IL}$, $\overline{\text{CAS}}$, Address Cycling: $t_{PC} = t_{PC \text{ min}}$)	-60	—	mA	1, 2, 3
		-70	—		
I_{CC5}	Standby Current (CMOS) Power Supply Standby Current ($\overline{\text{RAS}} = \overline{\text{CAS}} = V_{CC} - 0.2\text{V}$)	—	32	mA	
I_{CC6}	$\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Current Average Power Supply Current, $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Mode ($\overline{\text{RAS}}$, $\overline{\text{CAS}}$, Cycling: $t_{RC} = t_{RC \text{ min}}$)	-60	—	mA	1, 3, 4
		-70	—		
I_{IL}	Input Leakage Current Input Leakage Current, any input ($0.0 \leq V_{IN} \leq (V_{CC} - 6.0\text{V})$) All Other Pins Not Under Test = 0V	$\overline{\text{RAS}}$	-40	μA	
		$\overline{\text{CAS}}$	-40		
		All others	-160		
I_{OL}	Output Leakage Current (D_{OUT} is disabled, $0.0 \leq V_{OUT} \leq V_{CC}$)	-20	+20	μA	
V_{OH}	Output High Level Output "H" Level Voltage ($I_{OUT} = -4\text{mA}$ @ 2.4V)	2.4	—	V	
V_{OL}	Output Low Level Output "L" Level Voltage ($I_{OUT} = +4\text{mA}$ @ 0.4V)	—	0.4	V	
1. I_{CC1} , I_{CC3} , I_{CC4} and I_{CC6} depend on cycle rate. 2. I_{CC1} , I_{CC4} depend on output loading. Specified values are obtained with the output open. 3. Address can be changed once or less while $\overline{\text{RAS}} = V_{IL}$. In the case of I_{CC4} , it can be changed once or less when $\overline{\text{CAS}} = V_{IH}$ 4. Refresh current is specified for 1 bank..					

AC Characteristics $(T_A = 0 \text{ to } +70^\circ\text{C}, V_{CC} = 5 \pm 0.5\text{V})$

1. V_{IH} (min) and V_{IL} (max) are reference levels for measuring timing of input signals. Transition times are measured between V_{IH} and V_{IL} .
2. An initial pause of 100 μ s is required after power-up followed by 8 $\overline{\text{RAS}}$ only refresh cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycles instead of 8 $\overline{\text{RAS}}$ only refresh cycles is required. The DRAM Outputs will remain disabled until these 8 cycles have occurred. This prevents data contention (excessive current) during power on. To prevent excess power dissipation during power-up, $\overline{\text{RAS}}$ should rise coincident with the power supply voltage.
3. AC measurements assume $t_T = 5\text{ns}$.

Read, Write, and Refresh Cycles (Common Parameters)

Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t_{RC}	Random Read or Write Cycle Time	110	128K	130	128K	ns	
t_{RP}	$\overline{\text{RAS}}$ Precharge Time	40	—	50	—	ns	
t_{CP}	$\overline{\text{CAS}}$ Precharge Time	10	—	10	—	ns	
t_{RAS}	$\overline{\text{RAS}}$ Pulse Width	60	16K	70	16K	ns	
t_{CAS}	$\overline{\text{CAS}}$ Pulse Width	15	—	20	—	ns	
t_{ASR}	Row Address Setup Time	0	—	0	—	ns	
t_{RAH}	Row Address Hold Time	10	—	10	—	ns	
t_{ASC}	Column Address Setup Time	0	—	0	—	ns	
t_{CAH}	Column Address Hold Time	10	—	15	—	ns	
t_{RCD}	$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Delay Time	20	45	20	50	ns	1
t_{RAD}	$\overline{\text{RAS}}$ to Column Address Delay Time	10	—	15	—	ns	2
t_{RSH}	$\overline{\text{RAS}}$ Hold Time	15	—	20	—	ns	
t_{CSH}	$\overline{\text{CAS}}$ Hold Time	60	—	70	—	ns	
t_{CRP}	$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ Precharge Time	10	—	10	—	ns	
t_{DZC}	$\overline{\text{CAS}}$ Delay Time from D_{IN}	—	—	—	—	ns	3
t_T	Transition Time (Rise and Fall)	3	50	3	50	ns	
t_{AR}	Column Address Hold Time Referenced to $\overline{\text{RAS}}$	45	—	50	—	ns	

1. Operation within the t_{RCD} (max) limit ensures that t_{RAC} (max) can be met. t_{RCD} (max) is specified as a reference point only: if t_{RCD} is greater than the specified t_{RCD} (max) limit, then access time is controlled by t_{CAC} .

2. Operation within the t_{RAD} (max) limit ensures that t_{RAC} (max) can be met. t_{RAD} (max) is specified as a reference point only: If t_{RAD} is greater than the specified t_{RAD} (max) limit, then access time is controlled by t_{AA} .

3. This timing parameter is not applicable to this product, but applies to a related product in this family.

Write Cycle

Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t _{WCS}	Write Command Set Up Time	0	---	0	---	ns	
t _{WCH}	Write Command Hold Time	10	---	15	---	ns	
t _{Wp}	Write Command Pulse Width	10	---	15	---	ns	
t _{RWL}	Write Command to $\overline{\text{RAS}}$ Lead Time	15	---	20	---	ns	
t _{CWL}	Write Command to $\overline{\text{CAS}}$ Lead Time	15	---	20	---	ns	
t _{WCR}	Write Command Hold Time Referenced to $\overline{\text{RAS}}$	---	---	---	---	ns	1
t _{DHR}	Data Hold Time Referenced to $\overline{\text{RAS}}$	---	---	---	---	ns	1
t _{DS}	D _{IN} Setup Time	0	---	0	---	ns	
t _{DH}	D _{IN} Hold Time	10	---	15	---	ns	

1. This timing parameter is not applicable to this product, but applies to a related product in this family.

Read Cycle

Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t _{RAC}	Access Time from $\overline{\text{RAS}}$	---	60	---	70	ns	1, 2
t _{CAC}	Access Time from $\overline{\text{CAS}}$	---	15	---	20	ns	1, 2
t _{AA}	Access Time from Address	---	30	---	35	ns	1, 2
t _{RCS}	Read Command Setup Time	0	---	0	---	ns	
t _{RCH}	Read Command Hold Time to $\overline{\text{CAS}}$	0	---	0	---	ns	3
t _{RRH}	Read Command Hold Time to $\overline{\text{RAS}}$	0	---	0	---	ns	3
t _{RAL}	Column Address to $\overline{\text{RAS}}$ Lead Time	30	---	35	---	ns	
t _{CAL}	Column Address to $\overline{\text{CAS}}$ Lead Time	---	---	---	---	ns	4
t _{CLZ}	$\overline{\text{CAS}}$ to Output in Low-Z	0	---	0	---	ns	
t _{OH}	Output Data Hold Time	0	---	0	---	ns	
t _{CDD}	$\overline{\text{CAS}}$ to D _{IN} Delay Time	10	---	15	---	ns	
t _{OFF}	Output Buffer Turn-off Delay	0	10	0	15	ns	5

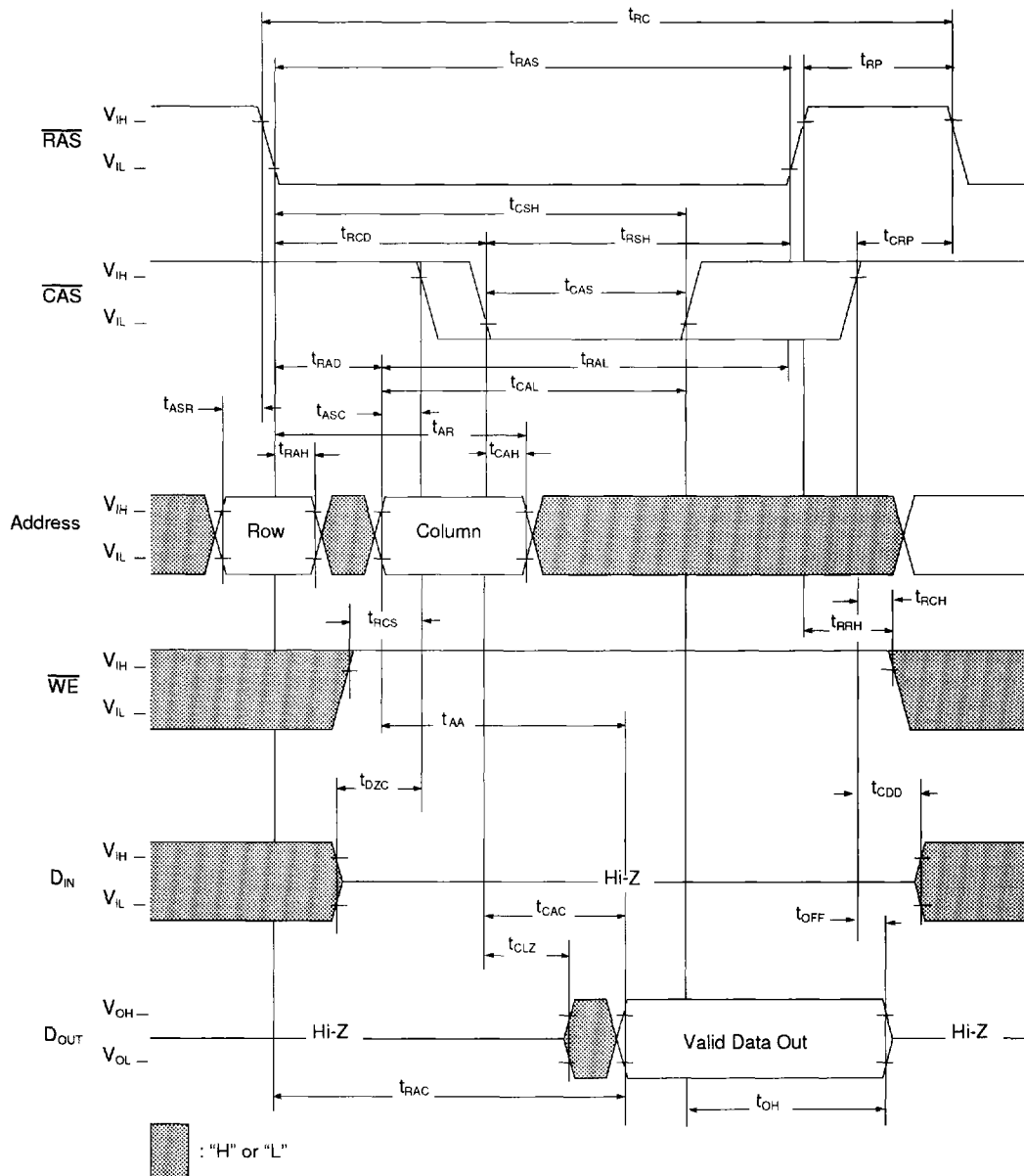
1. Measured with the specified current load and 100pF.
2. Access time is determined by the latter of t_{RAC}, t_{CAC}, t_{CPA}, t_{AA}.
3. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
4. This timing parameter is not applicable to this product, but applies to a related product in this family.
5. t_{OFF} (max) defines the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.

Fast Page Mode Cycle

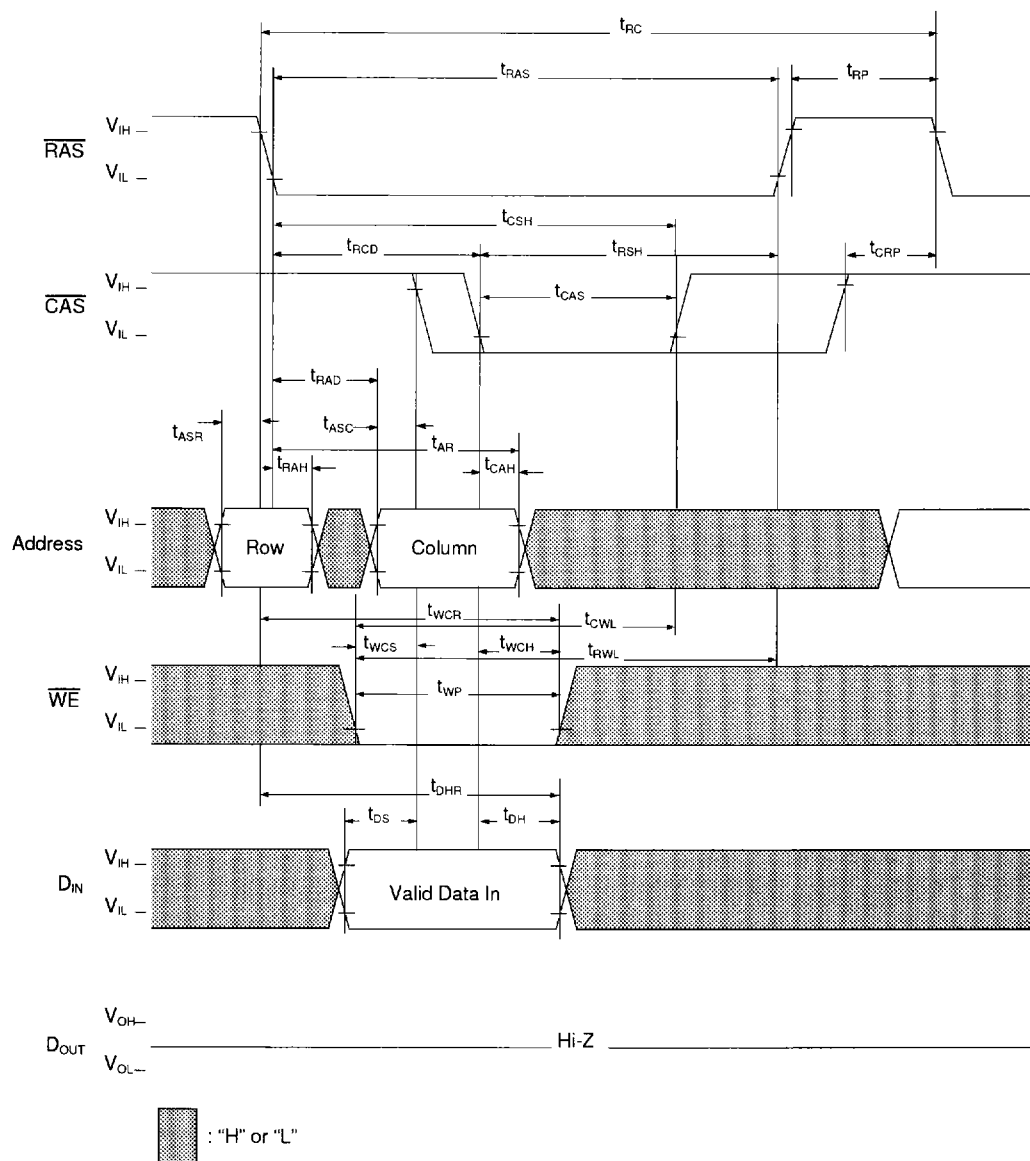
Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t_{PC}	Fast Page Mode Cycle Time	40	—	45	—	ns	
t_{RASP}	Fast Page Mode $\overline{RAS}$ Pulse Width	60	100K	70	100K	ns	
t_{CPRH}	$\overline{RAS}$ Hold Time from $\overline{CAS}$ Precharge	—	—	—	—	ns	1
t_{CPA}	Access Time from $\overline{CAS}$ Precharge	—	35	—	40	ns	2, 3
1. This timing parameter is not applicable to this product, but applies to a related product in this family. 2. Access time is determined by the latter of t_{RAC} , t_{CAC} , t_{CPA} , t_{AA} . 3. Access time assumes a load of 100pF.							

Refresh Cycle

Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t_{CHR}	$\overline{CAS}$ Hold Time ($\overline{CAS}$ before $\overline{RAS}$ Refresh Cycle)	15	—	15	—	ns	
t_{CSR}	$\overline{CAS}$ Setup Time ($\overline{CAS}$ before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{WRP}	$\overline{WE}$ Setup Time ($\overline{CAS}$ before $\overline{RAS}$ Refresh Cycle)	5	—	5	—	ns	
t_{WRH}	$\overline{WE}$ Hold Time ($\overline{CAS}$ before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{RPC}	$\overline{RAS}$ Precharge to $\overline{CAS}$ Hold Time	0	—	0	—	ns	
t_{REF}	Refresh Period	—	16	—	16	ms	1
1. 1024 refreshes are required every 16ms. The DC variation in the V_{CC} supply may not exceed 300mV within a refresh interval (16ms).							

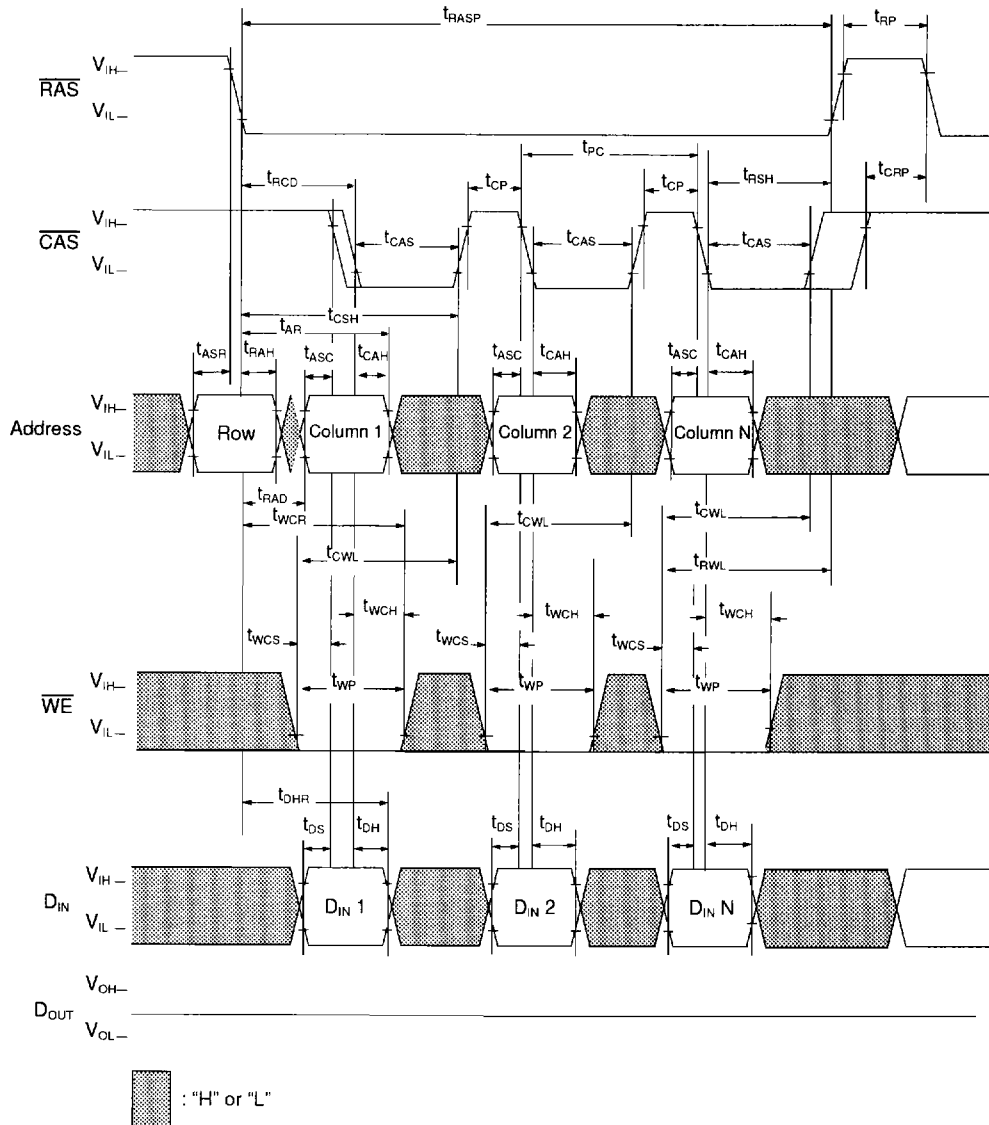


Write Cycle (Early Write)

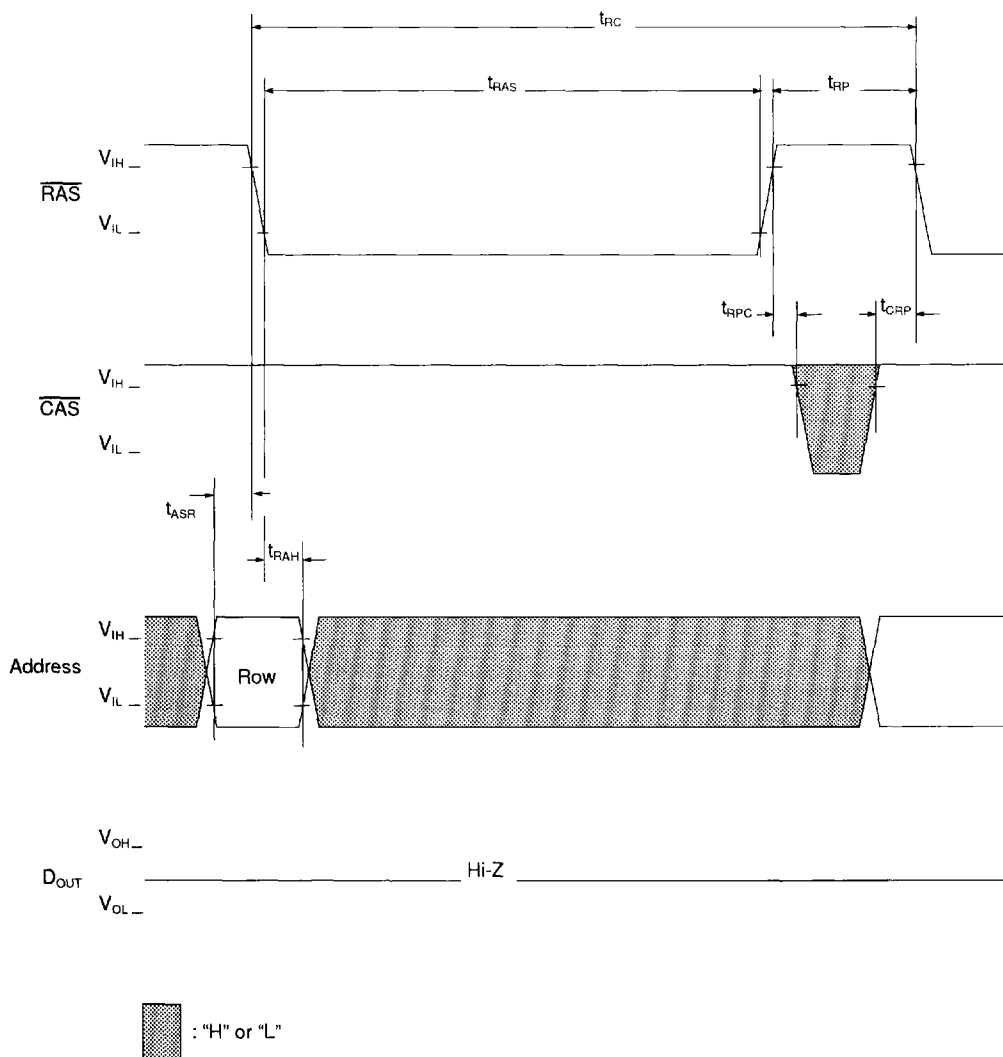


The diagram illustrates the timing relationships for a memory device. The signals shown are $\overline{\text{RAS}}$, $\overline{\text{CAS}}$, Address, $\overline{\text{WE}}$, D_{IN} , and D_{OUT} . The diagram is divided into sections for Row, Column 1, Column 2, and Column N. Key timing parameters include t_{RASP} , t_{CPRH} , t_{RP} , t_{RCD} , t_{CP} , t_{PC} , t_{SH} , t_{CRP} , t_{CAS} , t_{CAL} , t_{RAL} , t_{AR} , t_{RAH} , t_{ASC} , t_{CAH} , t_{ASR} , t_{RAD} , t_{RCS} , t_{RCH} , t_{RC} , t_{AA} , t_{CPA} , t_{OH} , t_{DZC} , t_{CDD} , t_{CAC} , t_{RAC} , t_{OFF} , t_{CLZ} , and t_{DZC} . A legend indicates that shaded areas represent "H" or "L" levels.

Fast Page Mode Write Cycle

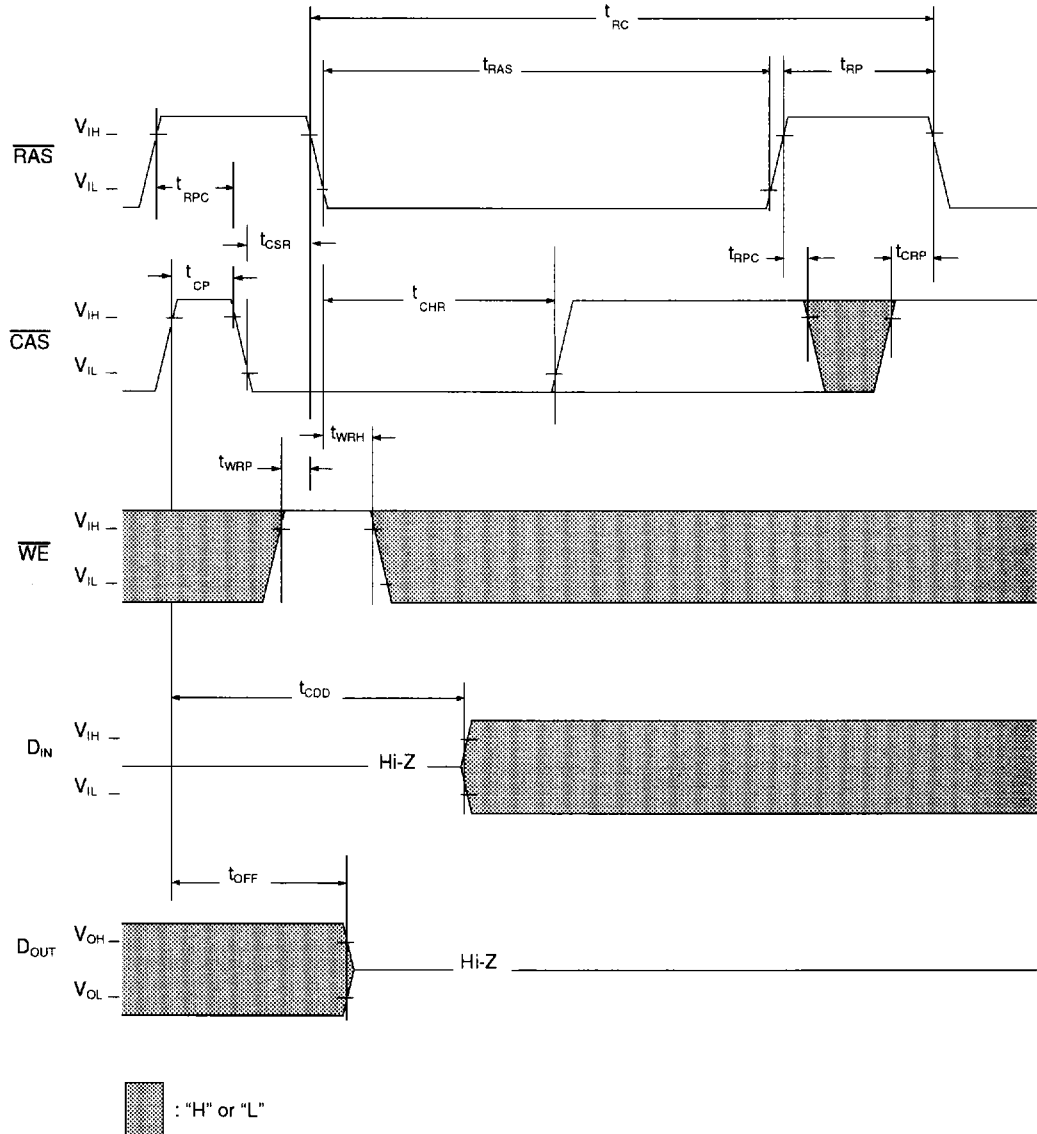


RAS Only Refresh Cycle

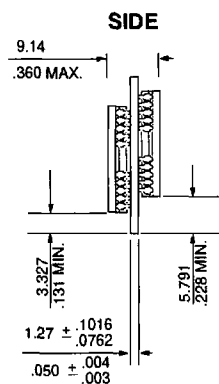
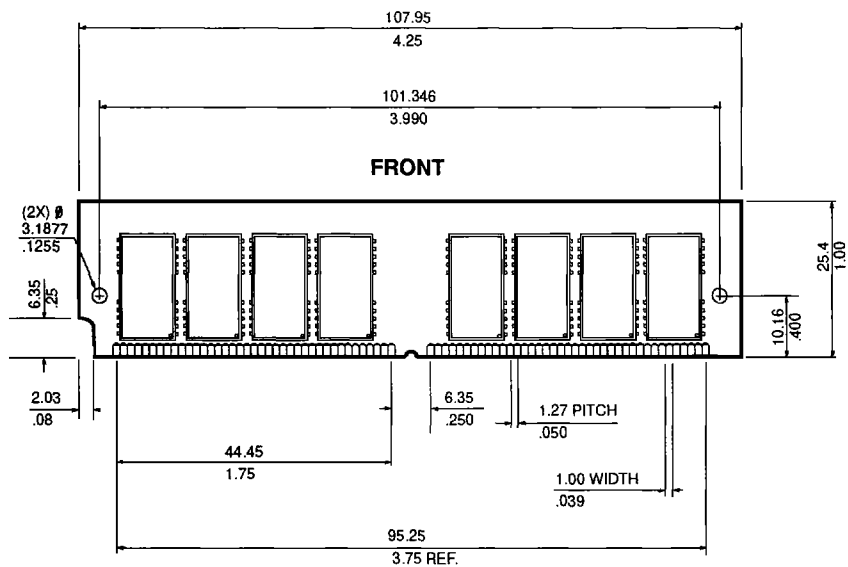


Note: $\overline{\text{WE}}$, D_{IN} are "H" or "L"

CAS Before RAS Refresh Cycle



Note: Addresses are "H" or "L"



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